

# RF Power Field Effect Transistors

## N-Channel Enhancement-Mode Lateral MOSFETs

Designed for W-CDMA and LTE base station applications with frequencies from 750 to 820 MHz. Can be used in Class AB and Class C for all typical cellular base station modulation formats.

- Typical Single-Carrier W-CDMA Performance:  $V_{DD} = 28$  Volts,  $I_{DQ} = 2000$  mA,  $P_{out} = 96$  Watts Avg., IQ Magnitude Clipping, Channel Bandwidth = 3.84 MHz, Input Signal PAR = 7.5 dB @ 0.01% Probability on CCDF.

| Frequency | $G_{ps}$<br>(dB) | $\eta_D$<br>(%) | Output PAR<br>(dB) | ACPR<br>(dBc) |
|-----------|------------------|-----------------|--------------------|---------------|
| 790 MHz   | 20.9             | 35.2            | 6.2                | -38.1         |
| 805 MHz   | 21.0             | 35.5            | 6.2                | -38.1         |
| 820 MHz   | 20.9             | 35.7            | 6.1                | -38.2         |

- Capable of Handling 10:1 VSWR, @ 32 Vdc, 805 MHz, 500 Watts CW Output Power (3 dB Input Overdrive from Rated  $P_{out}$ ), Designed for Enhanced Ruggedness
- Typical  $P_{out}$  @ 1 dB Compression Point = 340 Watts CW

### Features

- 100% PAR Tested for Guaranteed Output Power Capability
- Characterized with Series Equivalent Large-Signal Impedance Parameters and Common Source S-Parameters
- Internally Matched for Ease of Use
- Integrated ESD Protection
- Greater Negative Gate-Source Voltage Range for Improved Class C Operation
- Designed for Digital Predistortion Error Correction Systems
- Optimized for Doherty Applications
- In Tape and Reel. R6 Suffix = 150 Units, 56 mm Tape Width, 13-inch Reel.

**Table 1. Maximum Ratings**

| Rating                               | Symbol    | Value       | Unit |
|--------------------------------------|-----------|-------------|------|
| Drain-Source Voltage                 | $V_{DSS}$ | -0.5, +70   | Vdc  |
| Gate-Source Voltage                  | $V_{GS}$  | -6.0, +10   | Vdc  |
| Operating Voltage                    | $V_{DD}$  | 32, +0      | Vdc  |
| Storage Temperature Range            | $T_{stg}$ | -65 to +150 | °C   |
| Case Operating Temperature           | $T_C$     | 150         | °C   |
| Operating Junction Temperature (1,2) | $T_J$     | 225         | °C   |

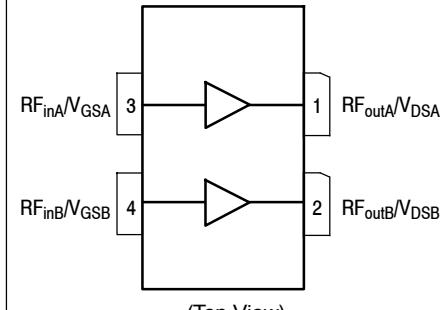
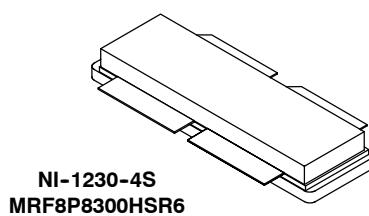
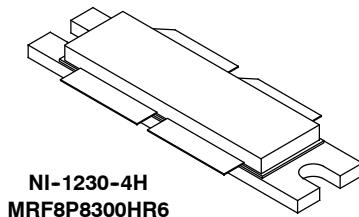
**Table 2. Thermal Characteristics**

| Characteristic  | Symbol          | Value (2,3)  | Unit |
|---|-----------------|--------------|------|
| Thermal Resistance, Junction to Case<br>Case Temperature 80°C, 96 W CW, 28 Vdc, $I_{DQ} = 2000$ mA, 820 MHz<br>Case Temperature 85°C, 300 W CW, 28 Vdc, $I_{DQ} = 2000$ mA, 820 MHz | $R_{\theta JC}$ | 0.26<br>0.21 | °C/W |

- Continuous use at maximum temperature will affect MTTF.
- MTTF calculator available at <http://www.freescale.com/rf>. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.
- Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to <http://www.freescale.com/rf>. Select Documentation/Application Notes - AN1955.

## MRF8P8300HR6 MRF8P8300HSR6

750-820 MHz, 96 W AVG., 28 V  
SINGLE W-CDMA  
LATERAL N-CHANNEL  
RF POWER MOSFETs



**Figure 1. Pin Connections**

**Table 3. ESD Protection Characteristics**

| Test Methodology                      | Class |
|---------------------------------------|-------|
| Human Body Model (per JESD22-A114)    | 2     |
| Machine Model (per EIA/JESD22-A115)   | A     |
| Charge Device Model (per JESD22-C101) | IV    |

**Table 4. Electrical Characteristics** ( $T_A = 25^\circ\text{C}$  unless otherwise noted)

| Characteristic  | Symbol    | Min | Typ | Max | Unit            |
|---|-----------|-----|-----|-----|-----------------|
| <b>Off Characteristics (1)</b>  |           |     |     |     |                 |
| Zero Gate Voltage Drain Leakage Current<br>( $V_{DS} = 70 \text{ Vdc}$ , $V_{GS} = 0 \text{ Vdc}$ ) | $I_{DSS}$ | —   | —   | 10  | $\mu\text{Adc}$ |
| Zero Gate Voltage Drain Leakage Current<br>( $V_{DS} = 28 \text{ Vdc}$ , $V_{GS} = 0 \text{ Vdc}$ ) | $I_{DSS}$ | —   | —   | 1   | $\mu\text{Adc}$ |
| Gate-Source Leakage Current<br>( $V_{GS} = 5 \text{ Vdc}$ , $V_{DS} = 0 \text{ Vdc}$ )              | $I_{GSS}$ | —   | —   | 1   | $\mu\text{Adc}$ |

**On Characteristics**

|   |                     |     |     |     |              |
|---|---------------------|-----|-----|-----|--------------|
| Gate Threshold Voltage (1)<br>( $V_{DS} = 10 \text{ Vdc}$ , $I_D = 400 \mu\text{Adc}$ )                           | $V_{GS(\text{th})}$ | 1.5 | 2.3 | 3.0 | $\text{Vdc}$ |
| Gate Quiescent Voltage<br>( $V_{DD} = 28 \text{ Vdc}$ , $I_{DQ} = 2000 \text{ mA}$ , Measured in Functional Test) | $V_{GS(Q)}$         | 2.3 | 3.1 | 3.8 | $\text{Vdc}$ |
| Drain-Source On-Voltage (1)<br>( $V_{GS} = 10 \text{ Vdc}$ , $I_D = 3 \text{ Adc}$ )                              | $V_{DS(\text{on})}$ | 0.1 | 0.2 | 0.3 | $\text{Vdc}$ |

**Functional Tests (2)** (In Freescale Test Fixture, 50 ohm system)  $V_{DD} = 28 \text{ Vdc}$ ,  $I_{DQ} = 2000 \text{ mA}$ ,  $P_{out} = 96 \text{ W Avg.}$ ,  $f = 820 \text{ MHz}$ , Single-Carrier W-CDMA, IQ Magnitude Clipping, Input Signal PAR = 7.5 dB @ 0.01% Probability on CCDF. ACPR measured in 3.84 MHz Channel Bandwidth @  $\pm 5 \text{ MHz}$  Offset.

|  |          |      |       |       |     |
|--|----------|------|-------|-------|-----|
| Power Gain   | $G_{ps}$ | 20.0 | 20.9  | 23.5  | dB  |
| Drain Efficiency   | $\eta_D$ | 34.5 | 35.7  | —     | %   |
| Output Peak-to-Average Ratio @ 0.01% Probability on CCDF | PAR      | 5.9  | 6.1   | —     | dB  |
| Adjacent Channel Power Ratio                             | ACPR     | —    | -38.2 | -36.5 | dBc |
| Input Return Loss  | IRL      | —    | -12   | -9    | dB  |

**Typical Performance over Frequency** (In Freescale Test Fixture, 50 ohm system)  $V_{DD} = 28 \text{ Vdc}$ ,  $I_{DQ} = 2000 \text{ mA}$ ,  $P_{out} = 96 \text{ W Avg.}$ , Single-Carrier W-CDMA, IQ Magnitude Clipping, Input Signal PAR = 7.5 dB @ 0.01% Probability on CCDF. ACPR measured in 3.84 MHz Channel Bandwidth @  $\pm 5 \text{ MHz}$  Offset.

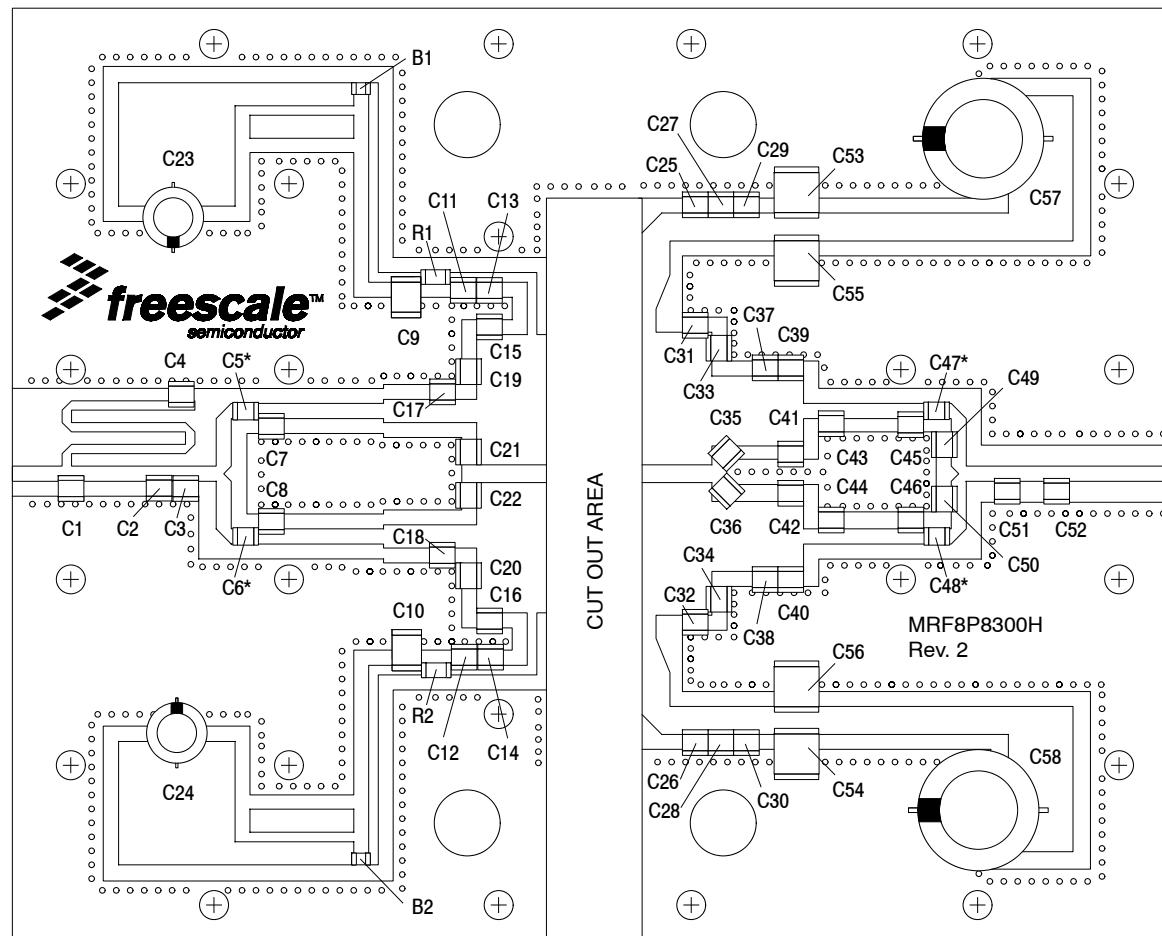
| Frequency | $G_{ps}$<br>(dB) | $\eta_D$<br>(%) | Output PAR<br>(dB) | ACPR<br>(dBc) | IRL<br>(dB) |
|-----------|------------------|-----------------|--------------------|---------------|-------------|
| 790 MHz   | 20.9             | 35.2            | 6.2                | -38.1         | -11         |
| 805 MHz   | 21.0             | 35.5            | 6.2                | -38.1         | -12         |
| 820 MHz   | 20.9             | 35.7            | 6.1                | -38.2         | -12         |

1. Each side of device measured separately.
2. Part internally matched both on input and output.

(continued)

**Table 4. Electrical Characteristics** ( $T_A = 25^\circ\text{C}$  unless otherwise noted) (continued)

| Characteristic   | Symbol             | Min | Typ    | Max | Unit                 |
|--|--------------------|-----|--------|-----|----------------------|
| <b>Typical Performances</b> (In Freescale Test Fixture, 50 ohm system) $V_{DD} = 28 \text{ Vdc}$ , $I_{DQ} = 2000 \text{ mA}$ , 790–820 MHz Bandwidth  |                    |     |        |     |                      |
| $P_{out}$ @ 1 dB Compression Point, CW   | P1dB               | —   | 340    | —   | W                    |
| IMD Symmetry @ 290 W PEP, $P_{out}$ where IMD Third Order Intermodulation $\leq 30 \text{ dBc}$<br>(Delta IMD Third Order Intermodulation between Upper and Lower Sidebands $> 2 \text{ dB}$ ) | IMD <sub>sym</sub> | —   | 35     | —   | MHz                  |
| VBW Resonance Point<br>(IMD Third Order Intermodulation Inflection Point)  | VBW <sub>res</sub> | —   | 35     | —   | MHz                  |
| Gain Flatness in 30 MHz Bandwidth @ $P_{out} = 96 \text{ W Avg.}$  | G <sub>F</sub>     | —   | 0.5    | —   | dB                   |
| Gain Variation over Temperature<br>( $-30^\circ\text{C}$ to $+85^\circ\text{C}$ )  | $\Delta G$         | —   | 0.0185 | —   | dB/ $^\circ\text{C}$ |
| Output Power Variation over Temperature<br>( $-30^\circ\text{C}$ to $+85^\circ\text{C}$ )  | $\Delta P_{1dB}$   | —   | 0.0076 | —   | dB/ $^\circ\text{C}$ |



\*C5, C6, C47, and C48 are mounted vertically.

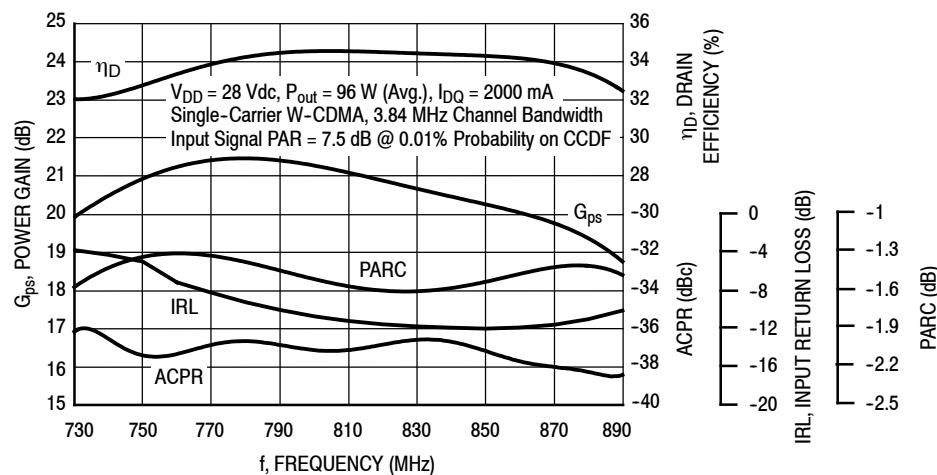
**Figure 2. MRF8P8300HR6(HSR6) Test Circuit Component Layout**

**Table 5. MRF8P8300HR6(HSR6) Test Circuit Component Designations and Values**

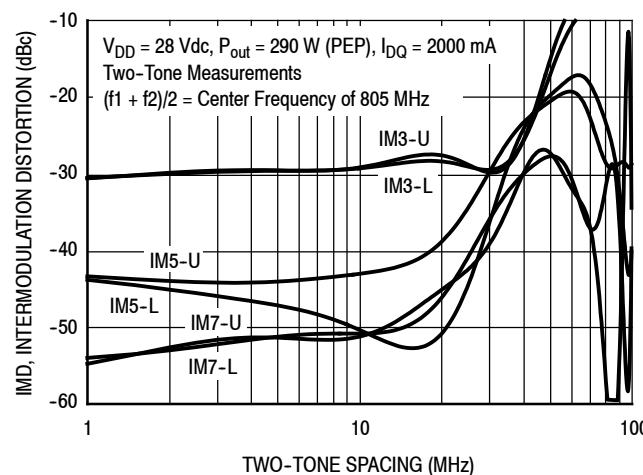
| Part                         | Description                               | Part Number          | Manufacturer |
|------------------------------|---|----------------------|--------------|
| B1, B2                       | Short Ferrite Beads                       | MPZ2012S300AT000     | TDK          |
| C1, C2, C39, C40, C41, C42   | 2.1 pF Chip Capacitors                    | ATC100B2R1BT500XT    | ATC          |
| C3, C49, C50                 | 1.0 pF Chip Capacitors                    | ATC100B1R0BT500XT    | ATC          |
| C4                           | 120 pF Chip Capacitor                     | ATC100B121JT500XT    | ATC          |
| C5, C6, C11, C12, C47, C48   | 39 pF Chip Capacitors                     | ATC100B390JT500XT    | ATC          |
| C7, C8, C45, C46             | 1.1 pF Chip Capacitors                    | ATC100B1R1BT500XT    | ATC          |
| C9, C10                      | 4.7 $\mu$ F, 50 V Chip Capacitors         | C4532X5R1H475KT      | TDK          |
| C13, C14, C19, C20, C25, C26 | 10 pF Chip Capacitors                     | ATC100B100JT500XT    | ATC          |
| C15, C16, C35, C36           | 4.7 pF Chip Capacitors                    | ATC100B4R7CT500XT    | ATC          |
| C17, C18                     | 4.3 pF Chip Capacitors                    | ATC100B4R3CT500XT    | ATC          |
| C21, C22                     | 8.2 pF Chip Capacitors                    | ATC100B8R2CT500XT    | ATC          |
| C23, C24                     | 22 $\mu$ F Electrolytic Capacitors        | UD1V220MCL1GS        | Nichicon     |
| C27, C28                     | 20 pF Chip Capacitors                     | ATC100B200JT500XT    | ATC          |
| C29, C30                     | 30 pF Chip Capacitors                     | ATC100B300JT500XT    | ATC          |
| C31, C32                     | 13 pF Chip Capacitors                     | ATC100B130JT500XT    | ATC          |
| C33, C34                     | 7.5 pF Chip Capacitors                    | ATC100B7R5CT500XT    | ATC          |
| C37, C38                     | 1.5 pF Chip Capacitors                    | ATC100B1R5BT500XT    | ATC          |
| C43, C44                     | 0.8 pF Chip Capacitors                    | ATC100B0R8BT500XT    | ATC          |
| C51, C52                     | 2.0 pF Chip Capacitors                    | ATC100B2R0BT500XT    | ATC          |
| C53, C54, C55, C56           | 22 $\mu$ F, 50 V Chip Capacitors          | C5750JF1H226ZT       | TDK          |
| C57, C58                     | 470 $\mu$ F, 63 V Electrolytic Capacitors | MCGPR63V477M13X26-RH | Multicomp    |
| R1, R2                       | 3 $\Omega$ Chip Resistors                 | CRCW12063R00FNEA     | Vishay       |
| PCB                          | 0.030", $\epsilon_r = 3.5$                | RF35A2               | Taconic      |

### MRF8P8300HR6 MRF8P8300HSR6

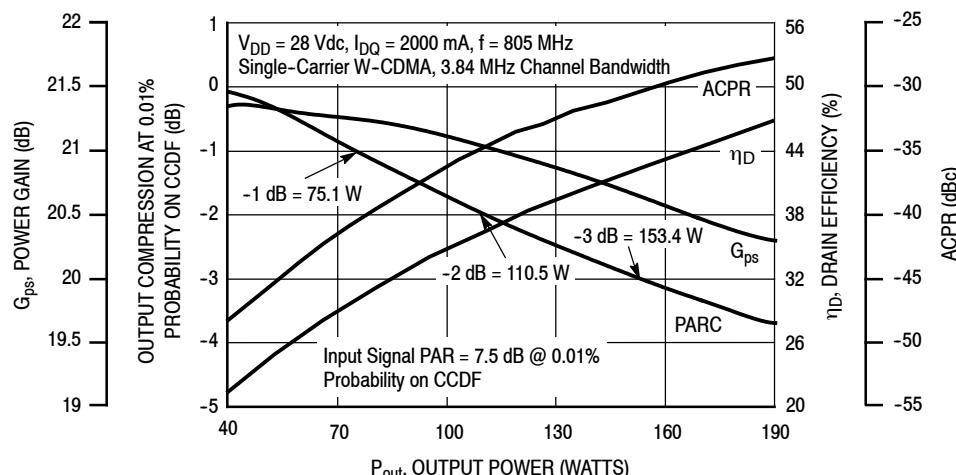
## TYPICAL CHARACTERISTICS



**Figure 3. Output Peak-to-Average Ratio Compression (PARC)  
Broadband Performance @ P<sub>out</sub> = 96 Watts Avg.**

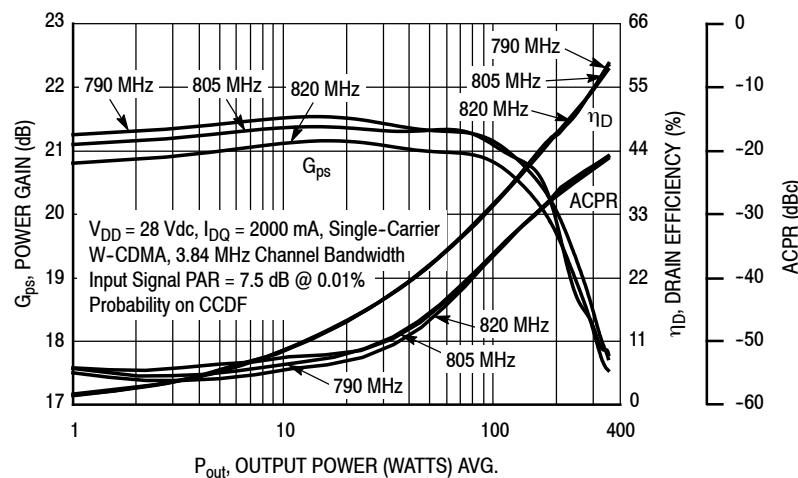


**Figure 4. Intermodulation Distortion Products  
versus Two-Tone Spacing**

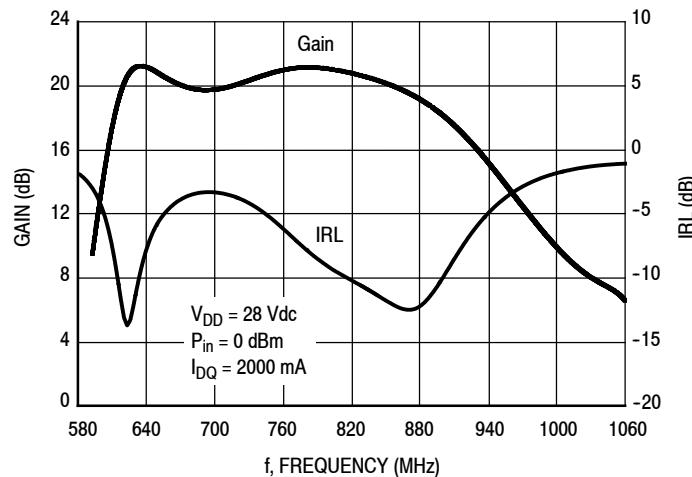


**Figure 5. Output Peak-to-Average Ratio  
Compression (PARC) versus Output Power**

## TYPICAL CHARACTERISTICS

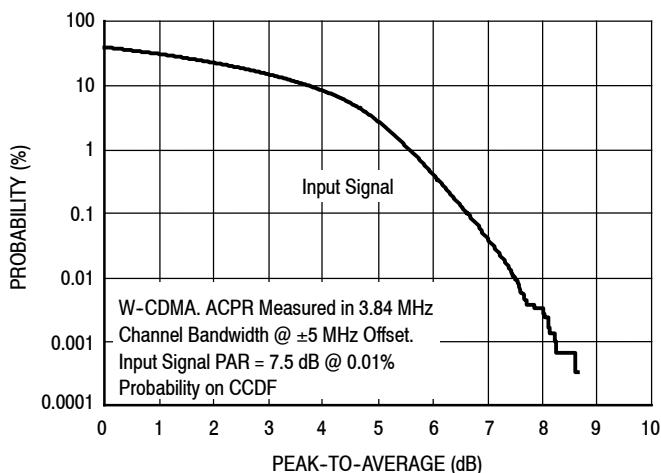


**Figure 6. Single-Carrier W-CDMA Power Gain, Drain Efficiency and ACPR versus Output Power**

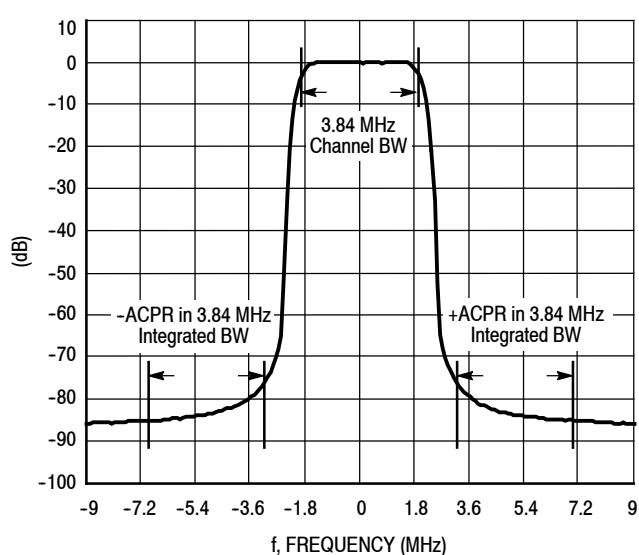


**Figure 7. Broadband Frequency Response**

## W-CDMA TEST SIGNAL



**Figure 8. CCDF W-CDMA IQ Magnitude Clipping, Single-Carrier Test Signal**



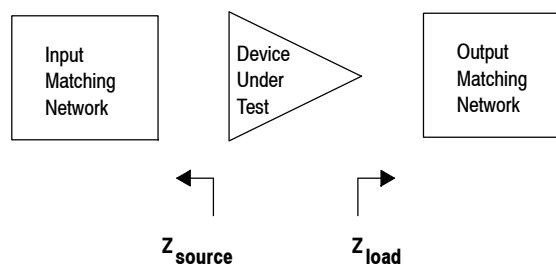
**Figure 9. Single-Carrier W-CDMA Spectrum**

$V_{DD} = 28$  Vdc,  $I_{DQ} = 2000$  mA,  $P_{out} = 96$  W Avg.

| f<br>MHz | $Z_{source}$<br>$\Omega$ | $Z_{load}$<br>$\Omega$ |
|----------|--------------------------|------------------------|
| 730      | 1.07 - j1.15             | 0.86 - j0.18           |
| 750      | 1.06 - j0.97             | 0.90 + j0.04           |
| 770      | 1.11 - j0.78             | 1.07 + j0.46           |
| 790      | 1.05 - j0.62             | 1.28 - j0.67           |
| 810      | 1.11 - j0.45             | 0.88 - j0.12           |
| 830      | 1.19 - j0.26             | 0.87 + j0.04           |
| 850      | 1.95 + j0.48             | 0.82 + j0.05           |
| 870      | 1.35 - j1.66             | 0.71 + j0.12           |
| 890      | 0.95 - j1.07             | 0.59 + j0.22           |

$Z_{source}$  = Test circuit impedance as measured from gate to ground, gate leads are tied together.

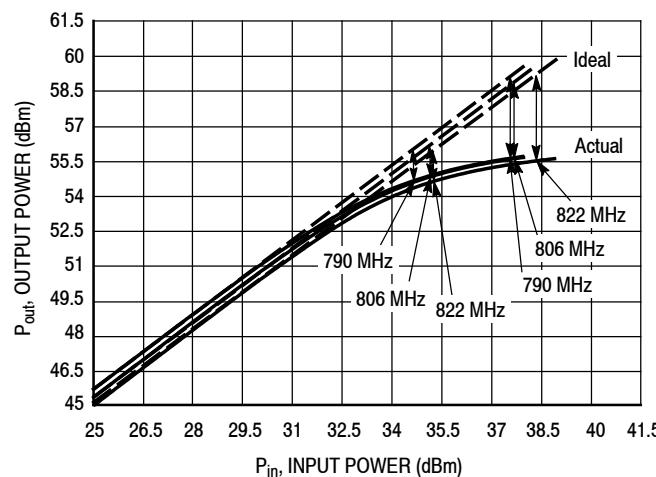
$Z_{load}$  = Test circuit impedance as measured from drain to ground, drain leads are tied together.



**Figure 10. Series Equivalent Source and Load Impedance**

## ALTERNATIVE PEAK TUNE LOAD PULL CHARACTERISTICS

$V_{DD} = 28$  Vdc,  $I_{DQA} = 1000$  mA, Pulsed CW, 10  $\mu$ sec(on), 10% Duty Cycle



NOTE: Load Pull Test Fixture Tuned for Peak P1dB Output Power @ 28 V

| f<br>(MHz) | P1dB  |      | P3dB  |      |
|------------|-------|------|-------|------|
|            | Watts | dBm  | Watts | dBm  |
| 790        | 288   | 54.6 | 363   | 55.6 |
| 806        | 299   | 54.8 | 366   | 55.6 |
| 822        | 287   | 54.6 | 349   | 55.4 |

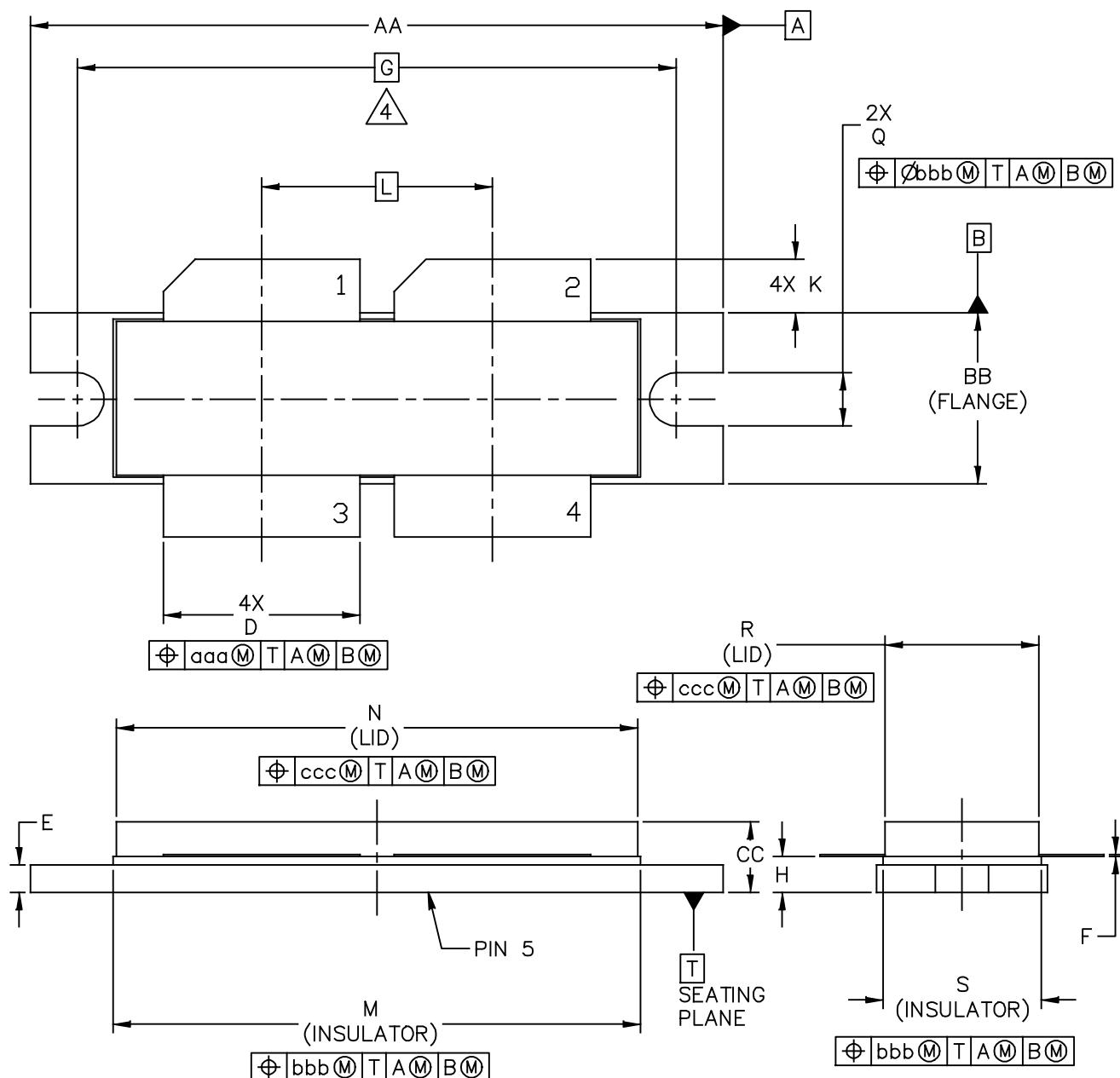
Test Impedances per Compression Level

| f<br>(MHz) |      | $Z_{source}$<br>$\Omega$ | $Z_{load}$<br>$\Omega$ |
|------------|------|--------------------------|------------------------|
| 790        | P1dB | 1.04 - j0.98             | 0.78 - j0.73           |
| 806        | P1dB | 1.16 - j1.39             | 0.76 - j0.71           |
| 822        | P1dB | 1.24 - j1.73             | 0.76 - j0.74           |

**Figure 11. Pulsed CW Output Power versus Input Power @ 28 V**

Note: Measurement made on a per side basis.

## PACKAGE DIMENSIONS



|   |                          |                            |
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| STANDARD: NON-JEDEC                                     |                          |                            |
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MRF8P8300HR6 MRF8P8300HSR6

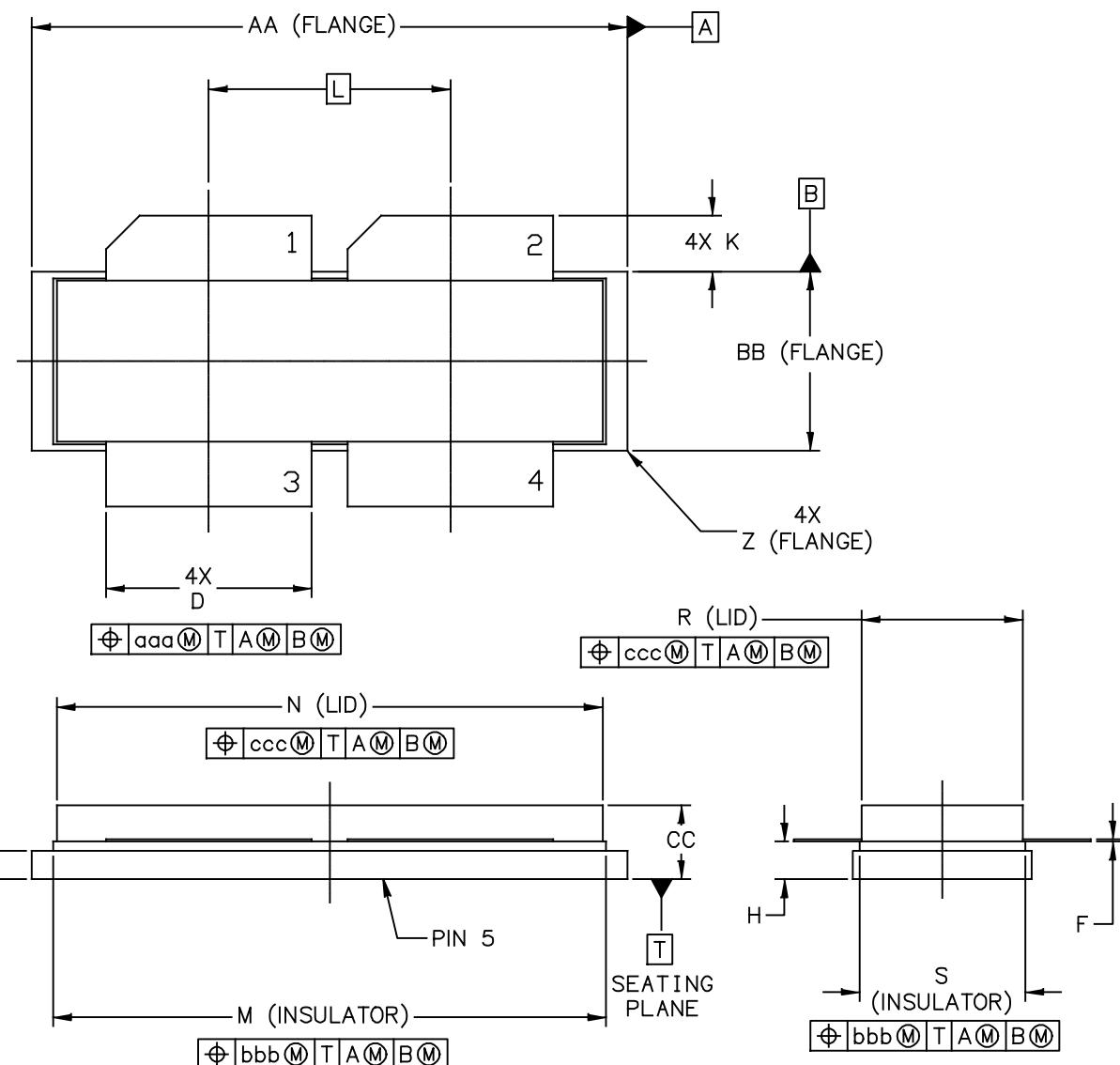
## NOTES:

1. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: INCH
3. DIMENSION H IS MEASURED .030 INCH (0.762 MM) AWAY FROM PACKAGE BODY.
-  4. RECOMMENDED BOLT CENTER DIMENSION OF 1.52 INCH (38.61 MM) BASED ON M3 SCREW.

| DIM | INCH  |       | MILLIMETER |       | DIM | INCH  |       | MILLIMETER |       |
|-----|-------|-------|------------|-------|-----|-------|-------|------------|-------|
|     | MIN   | MAX   | MIN        | MAX   |     | MIN   | MAX   | MIN        | MAX   |
| AA  | 1.615 | 1.625 | 41.02      | 41.28 | N   | 1.218 | 1.242 | 30.94      | 31.55 |
| BB  | .395  | .405  | 10.03      | 10.29 | Q   | .120  | .130  | 3.05       | 3.30  |
| CC  | .170  | .190  | 4.32       | 4.83  | R   | .355  | .365  | 9.02       | 9.27  |
| D   | .455  | .465  | 11.56      | 11.81 | S   | .365  | .375  | 9.27       | 9.53  |
| E   | .062  | .066  | 1.57       | 1.68  |     |       |       |            |       |
| F   | .004  | .007  | 0.10       | 0.18  |     |       |       |            |       |
| G   | 1.400 | BSC   | 35.56      | BSC   | aaa | .013  |       | 0.33       |       |
| H   | .082  | .090  | 2.08       | 2.29  | bbb | .010  |       | 0.25       |       |
| K   | .117  | .137  | 2.97       | 3.48  | ccc | .020  |       | 0.51       |       |
| L   | .540  | BSC   | 13.72      | BSC   |     |       |       |            |       |
| M   | 1.219 | 1.241 | 30.96      | 31.52 |     |       |       |            |       |

|   |                    |                            |
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## NOTES:

1. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: INCH
3. DIMENSION H IS MEASURED .030 INCH (0.762 MM) AWAY FROM PACKAGE BODY

| DIM | INCHES   |       | MILLIMETERS |       | DIM | INCHES |       | MILLIMETERS |       |
|-----|----------|-------|-------------|-------|-----|--------|-------|-------------|-------|
|     | MIN      | MAX   | MIN         | MAX   |     | MIN    | MAX   | MIN         | MAX   |
| AA  | 1.265    | 1.275 | 32.13       | 32.39 | R   | .355   | .365  | 9.02        | 9.27  |
| BB  | .395     | .405  | 10.03       | 10.29 | S   | .365   | .375  | 9.27        | 9.53  |
| CC  | .170     | .190  | 4.32        | 4.83  | Z   | R.000  | R.040 | R0.00       | R1.02 |
| D   | .455     | .465  | 11.56       | 11.81 |     |        |       |             |       |
| E   | .062     | .066  | 1.57        | 1.68  | aaa |        | .013  |             | 0.33  |
| F   | .004     | .007  | 0.10        | 0.18  | bbb |        | .010  |             | 0.25  |
| H   | .082     | .090  | 2.08        | 2.29  | ccc |        | .020  |             | 0.51  |
| K   | .117     | .137  | 2.97        | 3.48  |     |        |       |             |       |
| L   | .540 BSC |       | 13.72 BSC   |       |     |        |       |             |       |
| M   | 1.219    | 1.241 | 30.96       | 31.52 |     |        |       |             |       |
| N   | 1.218    | 1.242 | 30.94       | 31.55 |     |        |       |             |       |

|   |                    |                            |
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|                          | STANDARD: NON-JEDEC             |  |
|                          | 01 MAR 2013                     |  |

## PRODUCT DOCUMENTATION, SOFTWARE AND TOOLS

Refer to the following documents, tools and software to aid your design process.

### **Application Notes**

- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

### **Engineering Bulletins**

- EB212: Using Data Sheet Impedances for RF LDMOS Devices

### **Software**

- Electromigration MTTF Calculator
- RF High Power Model
- .s2p File

For Software and Tools, do a Part Number search at <http://www.freescale.com>, and select the “Part Number” link. Go to the Software & Tools tab on the part’s Product Summary page to download the respective tool.

## REVISION HISTORY

The following table summarizes revisions to this document.

| <b>Revision</b> | <b>Date</b> | <b>Description</b>  |
|-----------------|-------------|---|
| 0               | Jan. 2011   | <ul style="list-style-type: none"> <li>• Initial Release of Data Sheet</li> </ul>   |
| 1               | Apr. 2013   | <ul style="list-style-type: none"> <li>• Changed operating frequency from 790–820 MHz to 750–820 MHz due to expanded device frequency capability resulting from additional test data, p. 1</li> <li>• Table 3, ESD Protection Characteristics, removed the word “Minimum” after the ESD class rating. ESD ratings are characterized during new product development but are not 100% tested during production. ESD ratings provided in the data sheet are intended to be used as a guideline when handling ESD sensitive devices, p. 2</li> <li>• Replaced Case Outline 98ASB16977C, Issue E with Issue F, p. 9, 10. Changed dimension C from 0.150”–0.200” to CC 0.170”–0.190”.</li> <li>• Replaced Case Outline 98ARB18247C, Issue F with Issue G, p. 11, 12. Changed dimension C from 0.150”–0.200” to CC 0.170”–0.190”. Added minimum Z dimension R0.00”.</li> </ul> |

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